

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTORNEY DOCKET NO. 1945 P2/USA/SHICON/MBE

SERIAL NO. ^{031/382924}
N/A

LIST OF ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT Chow, et al

FILING DATE Herewith

GROUP ~~Unpublished~~ 176

U.S. PATENT DOCUMENTS

Examiner Initial		DOCKET NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>JHC</i>	A1	4	2	8	2	2	6	7	08/04/81	Kuyel	427	38	
<i>JHC</i>	A2	4	4	3	3	2	2	8	02/21/84	Nishimatsu, et al	219	10.55 R	
<i>JHC</i>	A3	4	4	6	5	5	3	2	08/14/84	Fukano	156	643	
<i>JHC</i>	A4	4	4	9	0	2	0	9	12/25/84	Hartman	156	643	
<i>JHC</i>	A5	4	5	0	2	9	1	4	03/05/85	Trumpp et al	156	643	
<i>JHC</i>	A6	4	5	7	6	6	9	2	03/18/86	Fukuta, et al	204	165	
<i>JHC</i>	A7	4	7	0	5	5	9	5	11/10/87	Okudaira et al	156	643	
<i>JHC</i>	A8	4	7	3	8	7	4	18	04/19/88	Kisa	156	643	
<i>JHC</i>	A9	4	7	8	6	3	5	2	11/22/88	Benzing	156	345	
<i>JHC</i>	A10	4	8	1	8	3	2	6	04/04/89	Liu, et al	156	345	
<i>JHC</i>	A11	4	8	3	1	9	6	3	05/23/89	Saito, et al	118	723	
<i>JHC</i>	A12	4	8	6	3	5	6	1	09/05/89	Freeman, et al	156	646	
<i>JHC</i>	A13	4	8	6	7	8	4	1	09/19/89	Loewenstein, et al	156	643	
<i>JHC</i>	A14	4	8	7	6	2	1	2	10/24/89	Koury	437	34	
<i>JHC</i>	A15	4	9	7	5	1	4	4	12/04/90	Yamazaki, et al	156	643	
<i>JHC</i>	A16	4	9	9	2	1	3	6	02/12/91	Tachi et al	156	643	
<i>JHC</i>	A17	4	9	9	4	4	1	0	02/19/91	Sun et al	437	192	
<i>JHC</i>	A18	5	0	0	2	6	3	2	03/26/91	Loewenstein, et al	156	643	
<i>JHC</i>	A19	5	0	1	3	3	9	8	05/07/91	Long et al	156	643	
<i>JHC</i>	A20	5	0	3	5	7	6	8	07/30/91	Mu et al	156	626	
<i>JHC</i>	A21	5	0	8	4	1	2	6	01/28/92	McKee	156	345	
<i>JHC</i>	A22	5	0	9	4	7	1	2	03/10/92	Becker et al	156	643	
<i>JHC</i>	A23	5	1	1	0	4	0	8	05/05/92	Fujii et al	156	643	
<i>JHC</i>	A24	5	1	1	0	4	1	1	05/05/92	Long	156	656	
<i>JHC</i>	A25	5	1	1	8	3	8	7	06/02/92	Kadomura	156	657	
<i>JHC</i>	A26	5	1	6	0	4	0	7	11/03/92	Latchford et al	156	656	
<i>JHC</i>	A27	5	1	6	4	3	3	0	11/17/92	Davis et al	437	192	
<i>JHC</i>	A28	5	1	7	6	7	9	2	01/05/93	Fallowan et al	156	652	
<i>JHC</i>	A29	5	1	8	8	9	8	0	02/23/93	Lai	437	193	
<i>JHC</i>	A30	5	1	9	2	7	0	2	03/09/93	Tseng	437	47	

EXAMINER

DATE CONSIDERED

EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTORNEY DOCKET NO. 1945 P2/USA/SILICON/MBE

C.G./362,924
SERIAL NO. N/A

LIST OF ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT Chow, et al

FILING DATE Herewith

GROUP Unknown 1746

U.S. PATENT DOCUMENTS

Examiner Initial		DOCKET NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	A31	5	2	5	6	2	4	5	10/26/93	Keller, et al.	156	643	
<i>See</i>	A32	5	2	8	2	8	9	9	02/01/94	Balmashonov, et al.	118	723 R	
<i>See</i>	A33	5	3	1	2	5	1	9	05/17/94	Sakai, et al.	134	1	
<i>See</i>	A34	5	3	1	8	6	6	8	06/07/94	Tamaki, et al.	156	662	
<i>See</i>	A35	5	3	3	8	3	9	8	08/16/94	Szwejkowski, et al.	156	655	
<i>See</i>	A36	5	3	5	4	4	1	7	10/11/94	Cheung, et al.	156	643	
<i>See</i>	A37	5	3	5	6	4	7	8	10/18/94	Chen, et al.	134	1	
<i>See</i>	A38	5	3	5	8	6	0	1	10/25/94	Cathey	156	656	
<i>See</i>	A39	5	3	8	2	3	1	6	01/17/95	Hills, et al.	156	643	
<i>See</i>	A40	5	4	1	3	9	5	4	05/09/95	Aydil, et al.	437	81	
<i>See</i>	A41	5	4	3	1	7	7	2	07/11/95	Babie, et al.	156	643 1	
<i>See</i>	A42	5	4	4	3	6	8	6	08/22/95	Jones, et al.	216	37	
<i>See</i>	A43	5	4	4	9	4	1	1	09/12/95	Fukuda, et al.	118	723 MP	
<i>See</i>	A44	5	5	1	4	6	2	2	05/07/96	Bornstein, et al.	437	189	
<i>See</i>	A45	5	5	2	1	1	1	9	05/28/96	Chen, et al.	437	187	
<i>See</i>	A46	5	5	2	9	1	9	7	06/25/96	Grewal	216	68	
<i>See</i>	A47	5	6	2	4	6	1	5	04/15/97	Keller	438	720	
<i>See</i>	A48	5	6	2	6	7	7	5	05/06/97	Roberts, et al.	216	67	
<i>See</i>	A49	5	6	4	4	1	5	3	07/01/97	Keller	257	324	
<i>See</i>	A50	5	7	5	3	5	3	3	05/19/98	Saito	437	192	
<i>See</i>	A51	5	7	5	6	4	0	0	05/26/98	Ye, et al.	438	710	
<i>See</i>	A52	5	8	6	6	4	8	3	02/02/99	Shiau, et al.	438	720	
<i>See</i>	A53	5	8	7	4	3	6	3	02/23/99	Hoh, et al.	438	721	
<i>See</i>	A54	5	8	7	9	5	7	5	03/09/99	Tepman, et al.	216	68	
	A55												
	A56												
	A57												
	A58												
	A59												
	A60												

EXAMINER

DATE CONSIDERED

EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTORNEY DOCKET NO. 1945 P2/USA/SILICON/MBE

C9/22/92
SERIAL NO. N/A

LIST OF ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT Chow, et al

FILING DATE: Herewith

GROUP Unknown 1746

FOREIGN PATENT DOCUMENTS

		DOCKET NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
													YES	NO
<i>See</i>	B1	0	4	6	3	3	7	3	01/02/92	EP Application	<u> </u>	<u> </u>		
<i>See</i>	B2	0	5	1	6	0	4	3	12/02/92	EP Application	<u> </u>	<u> </u>		
<i>See</i>	B3	0	5	5	5	5	4	6	08/18/93	EP Application	<u> </u>	<u> </u>		
<i>See</i>	B4	0	6	9	7	4	6	7	02/21/96	EP Application	<u> </u>	<u> </u>		
<i>See</i>	B5	4	1	3	2	5	5	9	04/08/93	German Application	<u> </u>	<u> </u>	✓	
<i>See</i>	B6	9	6	1	5	5	4	5	05/23/96	PCT	<u> </u>	<u> </u>		
	B7													
	B8													
	B9													
	B10													
	B11													
	B12													
	B13													
	B14													
	B15													
	B16													
	B17													
	B18													
	B19													
	B20													
	B21													
	B22													
	B23													
	B24													
	B25													
	B26													
	B27													
	B28													

EXAMINER

DATE CONSIDERED 2/3/91

EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTORNEY DOCKET NO. 1945 P2/USA/SILICON/MBE

SERIAL NO. ^{258/262,924} N/A**LIST OF ART CITED BY APPLICANT**

(Use several sheets if necessary)

APPLICANT Chow, et al

FILING DATE Herewith

GROUP ~~Unknown~~ ^{174C}**OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)**

<i>file</i>	C1	Avdil, et al., "Multiple Steady States in a Radio Frequency Chlorine Glow Discharge," <u>J-Appl-Phys.</u> , Volume 69, No. 1, January 1, 1991, pages 109-114
<i>file</i>	C2	Hillenius, S.J., et al., "A Symmetric Submicron CMOS Technology," <u>IEEE</u> , pages 252-255, 1986 ✓
<i>file</i>	C3	PCT Notification of International Search Report dated February 4, 1999
	C4	
	C5	
	C6	
	C7	
	C8	
	C9	
	C10	
	C11	
	C12	
	C13	
	C14	
	C15	
	C16	
	C17	
	C18	
	C19	
	C20	

EXAMINER

DATE CONSIDERED

EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered
Include copy of this form with next communication to applicant